

**Search Notes**

Application/Control No.

10/653,242

Examiner

John S. Chu

Applicant(s)/Patent under  
Reexamination

FUJITA ET AL.

Art Unit

1752

**SEARCHED**

Class	Subclass	Date	Examiner
430	157	4/2006	JL
430	176		
430	183		
430	184		
430	185		
430	186		
430	187		
534	560		

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
EAST SEARCH UPDATED	4/2006	JL
INVENTOR SEARCH		
STRUCTURE SEARCH UPDATED		

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner
430	157,176		
430	183,184		
430	185,186		
430/187			

<b>Search Notes (continued)</b> 	Application/Control No.	Applicant(s)/Patent under Reexamination
	10/653,242	FUJITA ET AL.
Examiner	Art Unit	
John S. Chu	1752	

**SEARCHED**

INTERFERENCE SEARCHED			
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534	560	4/20/66	JL